



HUIZHOU JINSANE ELECTRONICS CO., LTD

SI2300

20V N-Channel Enhancement Mode MOSFET

VDS= 20V

RDS(ON), Vgs@ 4.5V, Ids@ 3.6A <70mΩ

RDS(ON), Vgs@ 2.5V, Ids@ 3.1A <80mΩ

Features

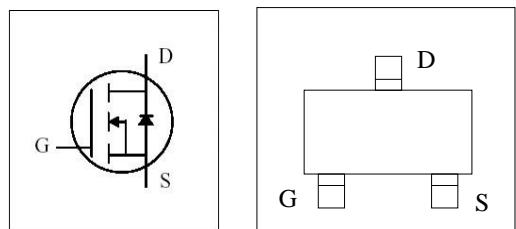
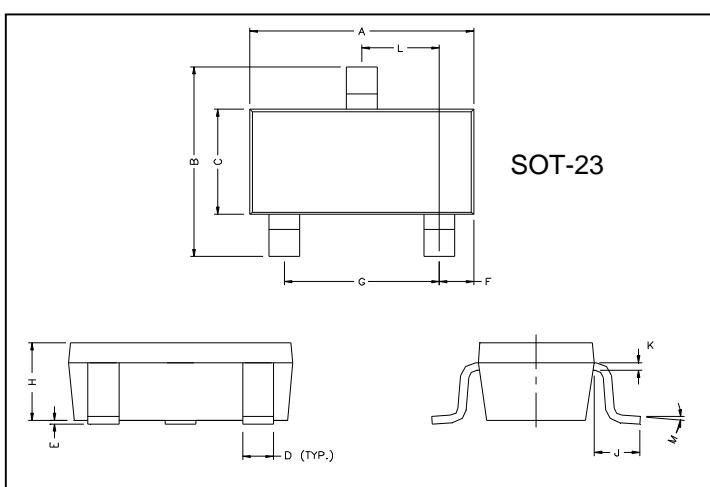
Advanced trench process technology

High Density Cell Design For Ultra Low On-Resistance

High Power and Current handling capability

Ideal for Li ion battery pack applications

Package Dimensions



| REF. | Millimeter | | REF. | Millimete | |
|------|------------|------|------|-----------|------|
| | Min. | Max. | | Min. | Max. |
| A | 2.80 | 3.00 | G | 1.80 | 2.00 |
| B | 2.30 | 2.50 | H | 0.90 | 1.1 |
| C | 1.20 | 1.40 | K | 0.10 | 0.20 |
| D | 0.30 | 0.50 | J | 0.35 | 0.70 |
| E | 0 | 0.10 | L | 0.92 | 0.98 |
| F | 0.45 | 0.55 | M | 0° | 10° |

Maximum Ratings and Thermal Characteristics (TA = 25°C unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|--|-----------------------------------|----------------|------|
| Drain-Source Voltage | V _{DS} | 20 | V |
| Gate-Source Voltage | V _{GS} | ± 12 | |
| Continuous Drain Current | I _D | 3.6 | A |
| Pulsed Drain Current ¹⁾ | I _{DM} | 8 | |
| Maximum Power Dissipation | TA = 25°C | P _D | 1.25 |
| | TA = 75°C | | 0.8 |
| Operating Junction and Storage Temperature Range | T _J , T _{stg} | -55 to 150 | °C |
| Junction-to-Ambient Thermal Resistance (PCB mounted) ²⁾ | R _{θJA} | 78 | °C/W |

Notes

1) Pulse width limited by maximum junction temperature.

2) Surface Mounted on FR4 Board, t ≤ 5 sec.

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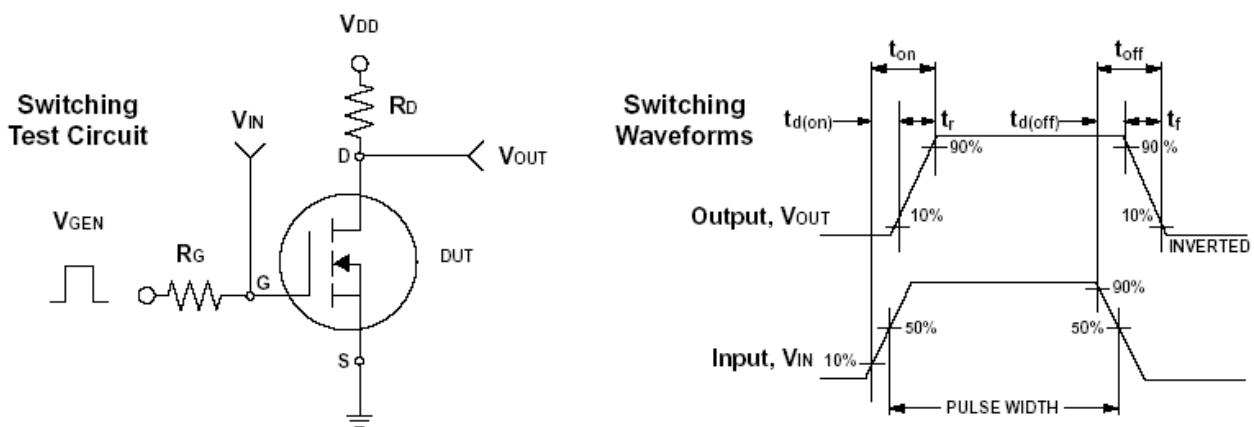
ELECTRICAL CHARACTERISTICS (TA = 25°C unless otherwise noted)

| Parameter | Symbol | Test Condition | Min. | Typ. | Max. | Unit |
|-----------------------------------|---------------------|--|------|------|------|------|
| Static³⁾ | | | | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} | V _{GS} = 0V, I _D = 250μA | 20 | | | V |
| Drain-Source On-State Resistance | R _{DS(on)} | V _{GS} = 2.5V, I _D = 3.1A | | 70.0 | 80.0 | mΩ |
| Drain-Source On-State Resistance | R _{DS(on)} | | | 60.0 | 70.0 | |
| Gate Threshold Voltage | V _{GS(th)} | V _{DS} = V _{GS} , I _D = 250μA | 0.6 | 0.76 | | V |
| Zero Gate Voltage Drain Current 0 | I _{DSS} | V _{DS} = 20V, V _{GS} = 0V | | | 1 | μA |
| Gate Body Leakage | I _{GSS} | V _{GS} = ± 12V, V _{DS} = 0V | | | ±100 | nA |
| Forward Transconductance | g _f | V _{DS} = 5V, I _D = 4.2A | | 5 | — | S |
| Dynamic⁴⁾ | | | | | | |
| Total Gate Charge | Q _g | V _{DS} = 10V, I _D = 3.6A V _{GS} = 4.5V | | 5.4 | 10 | nC |
| Gate-Source Charge | Q _{gs} | | | 0.65 | | |
| Gate-Drain Charge | Q _{gd} | | | 1.5 | | |
| Turn-On Delay Time | t _{d(on)} | V _{DD} = 10V, R _G = 6Ω I _D = 1A, V _{GS} = 4.5V RL = 5.5Ω | | 12 | 25 | ns |
| Turn-On Rise Time | t _r | | | 36 | 60 | |
| Turn-Off Delay Time | t _{d(off)} | | | 34 | 60 | |
| Turn-Off Fall Time | t _f | | | 10 | 25 | |
| Input Capacitance | C _{iss} | V _{DS} = 10V, V _{GS} = 0V f = 1.0 MHz | | 340 | | pF |
| Output Capacitance | C _{oss} | | | 115 | | |
| Reverse Transfer Capacitance | C _{rss} | | | 33 | | |
| Source-Drain Diode | | | | | | |
| Max. Diode Forward Current | I _s | | | | 1.6 | A |
| Diode Forward Voltage | V _{SD} | I _s = 1.0A, V _{GS} = 0V | | | 1.0 | V |

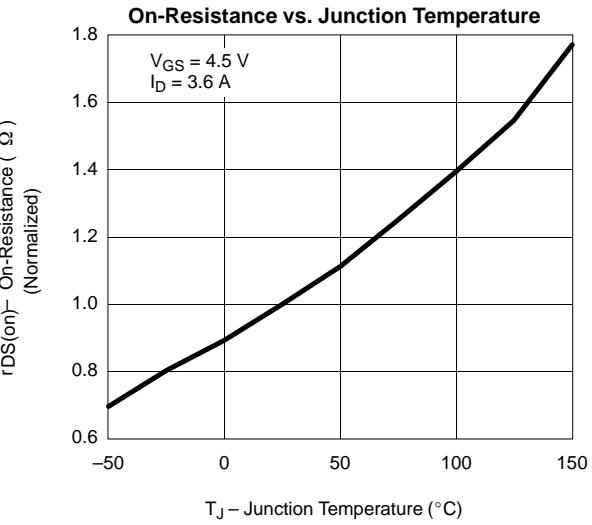
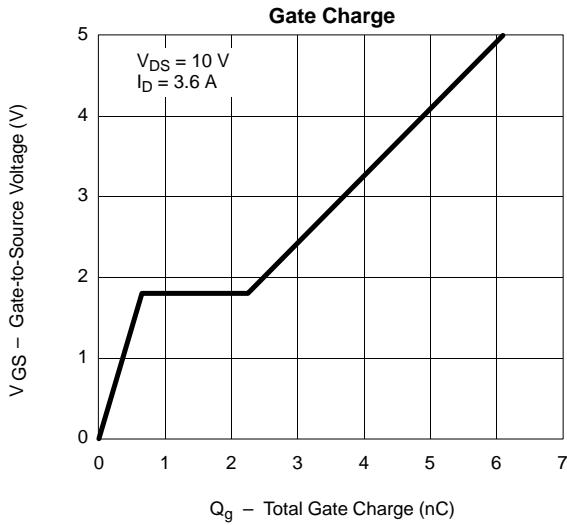
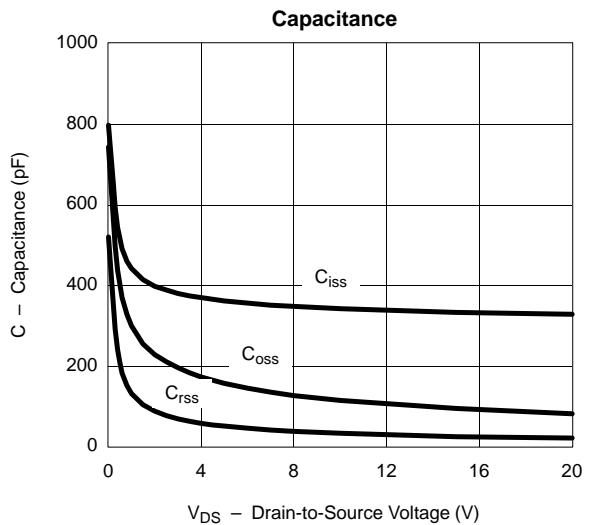
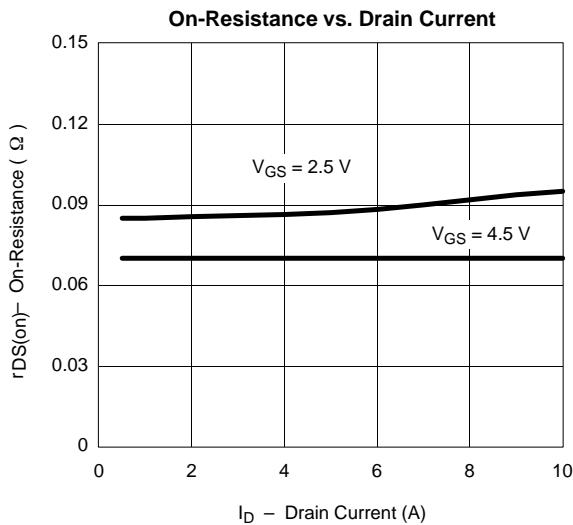
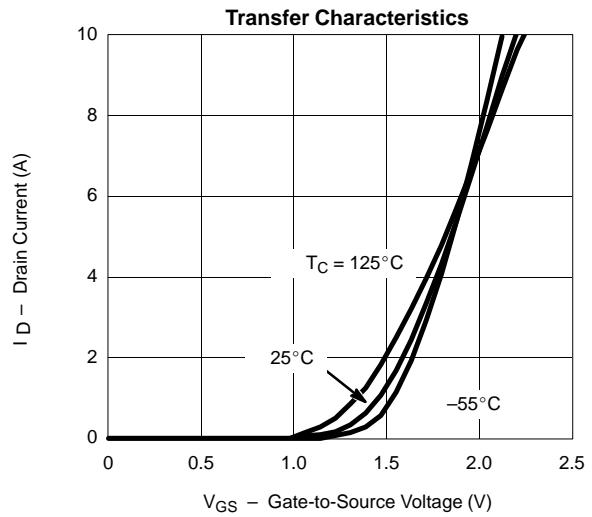
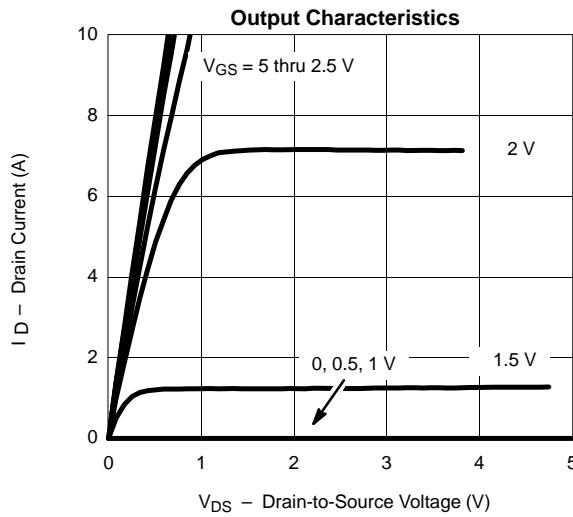
Notes

3) Short duration test pulse used to minimize self-heating effect.

4) Pulse test pulse width <= 300μs, duty cycle <= 2%.



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